

Search Notes

Application/Control No.

10/057,179

Examiner

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Applicant(s)/Patent under
Reexamination

MA ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	229-236	3/31/2006	JP
	316	6/30/2005	JP
	346	6/30/2005	JP
	348	6/30/2005	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	229	6/30/2006	JP
	230	6/30/2006	JP
	232	6/30/2006	JP

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT/USPGPUB EPO/JPO	6/30/2005	JP
Inventor Name Search East/EDAN	6/30/2005	JP
IEEE Iterative AND channel AND estimate	6/30/2005	JP